

# Abstracts

## Extraction of parasitic parameters of dummy devices on different silicon substrates (1998 [RFIC])

*L.P. Chen, Y.P. Ho, D.C. Lin, B.M. Tseng, H.Y. Lee, R.F. Guan, G.W. Huang, Y.C. Chen, W.Y. Wen and C.L. Chen. "Extraction of parasitic parameters of dummy devices on different silicon substrates (1998 [RFIC])." 1998 Radio Frequency Integrated Circuits (RFIC) Symposium 98. (1998 [RFIC]): 321-324.*

S-parameters of dummy devices fabricated on Si substrates with different resistivities are measured and analyzed to study the effects of substrate resistivity on the microwave characteristics. An equivalent parasitic circuit model is proposed and the extraction procedure also developed. The substrate resistivity effects can be explained well by the proposed model.

[Return to main document.](#)